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					First Named Inventor	Mei-Ling Wu				
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					Examiner Name					
Sheet		1	of	1	Attorney Docket Number	284867-0	00040			
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8m		KAZUHIKO ENDO ET AL., "Nitrogen doped fluorinated amorphous carbon thin films grown by plasma enhanced chemical vapor deposition for low dielectric constant interlayer dielectrics", Appl. Phys. Lett., June 17, 1996, pp. 3656-3658, Vol. 68, No. 25.								
Eu			T.E. KARIS ET AL., "Ellipsometric measurement of solid fluorocarbon film thickness on magnetic recording media", <i>J. Appl. Phys.</i> , April 15, 1997, pp. 5378-5380, Vol. 81, No. 8.							
Our			T.E. KARIS ET AL., "Characterization of a solid fluorocarbon film on magnetic recording media", J. Vac. Sci. Technol., Jul/Aug 1997, pp. 2382-2387, Vol. 15, No. 4.							
BU	•		T. E. KARIS ET AL., "Tribology of a Solid Fluorocarbon Film on Magnetic Recording Media", IEEE Transactions on Magnetics, July 1998, pp. 1747-1749, Vol. 34, No. 4.							
Ou		J. LUBGUBAN JR. ET AL., "Thermal stability and breakdown strength of carbon-doped SiO ₂ :F films prepared by plasma-enhanced chemical vapor deposition method", <i>Journal of Applied Physics</i> , April 15, 2000, pp. 3715-3722, Vol. 87, No. 8.								

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			ind Code ² if known)			
Ru	7	4,693,799		Yanagihara et al.	09-15-1987	
ST.	-	5,674,638		Grill et al.	10-07-1997	
	 					
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